## Notice of References Cited Application/Control No. O9/912,721 Examiner JOHN J. LEE Applicant(s)/Patent Under Reexamination CHEN ET AL. Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,405,309	06-2002	Cheng et al.	713/1
*	В	US-6,751,478	06-2004	Sakai et al.	455/560
*	С	US-7,032,223	04-2006	Liu, Ming-Kang	719/310
*	D	US-7,062,769	06-2006	Ma et al.	719/312
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-		·	,
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Р					
	α					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	V	
	×	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.